

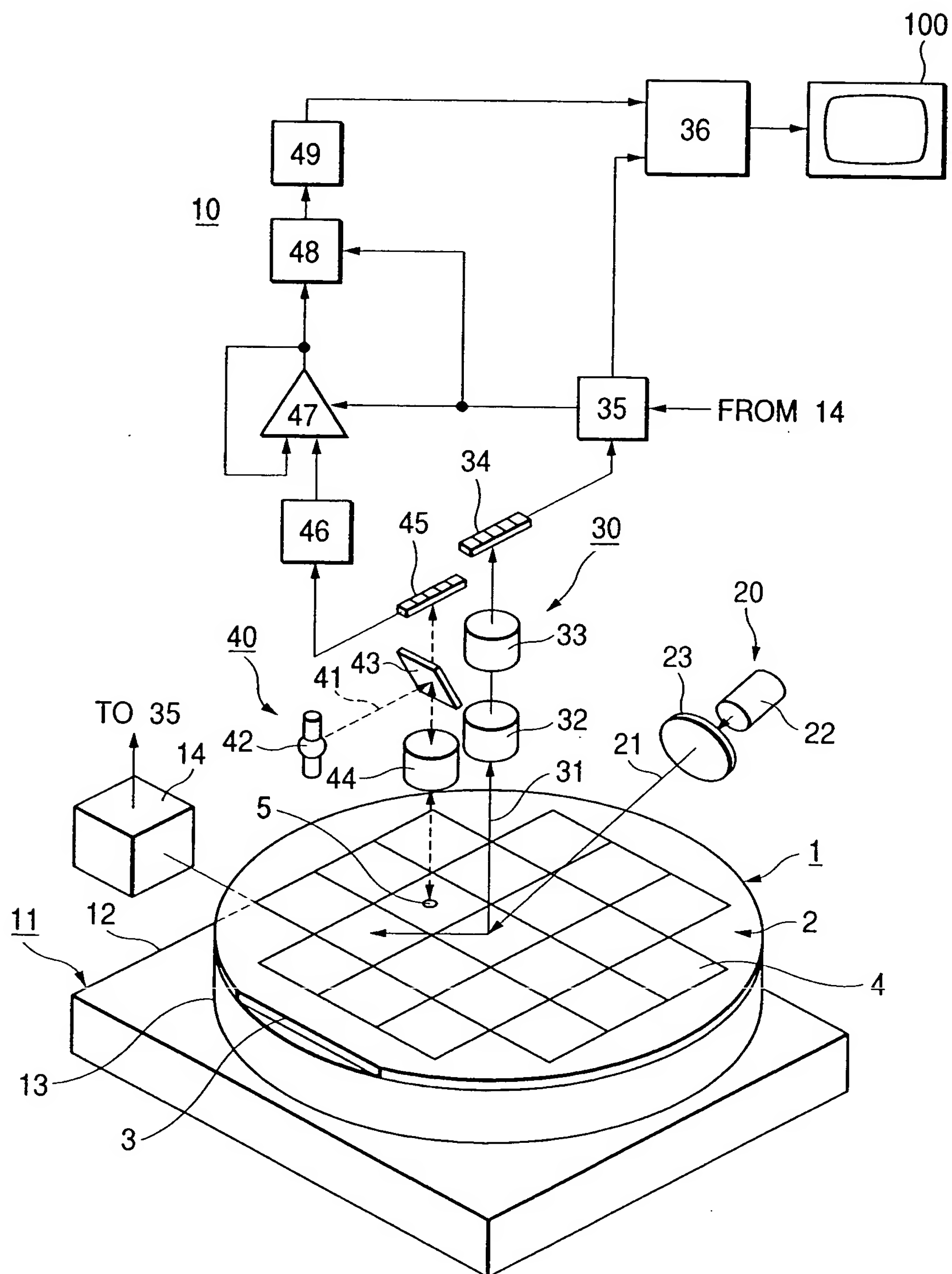
FIG. 1

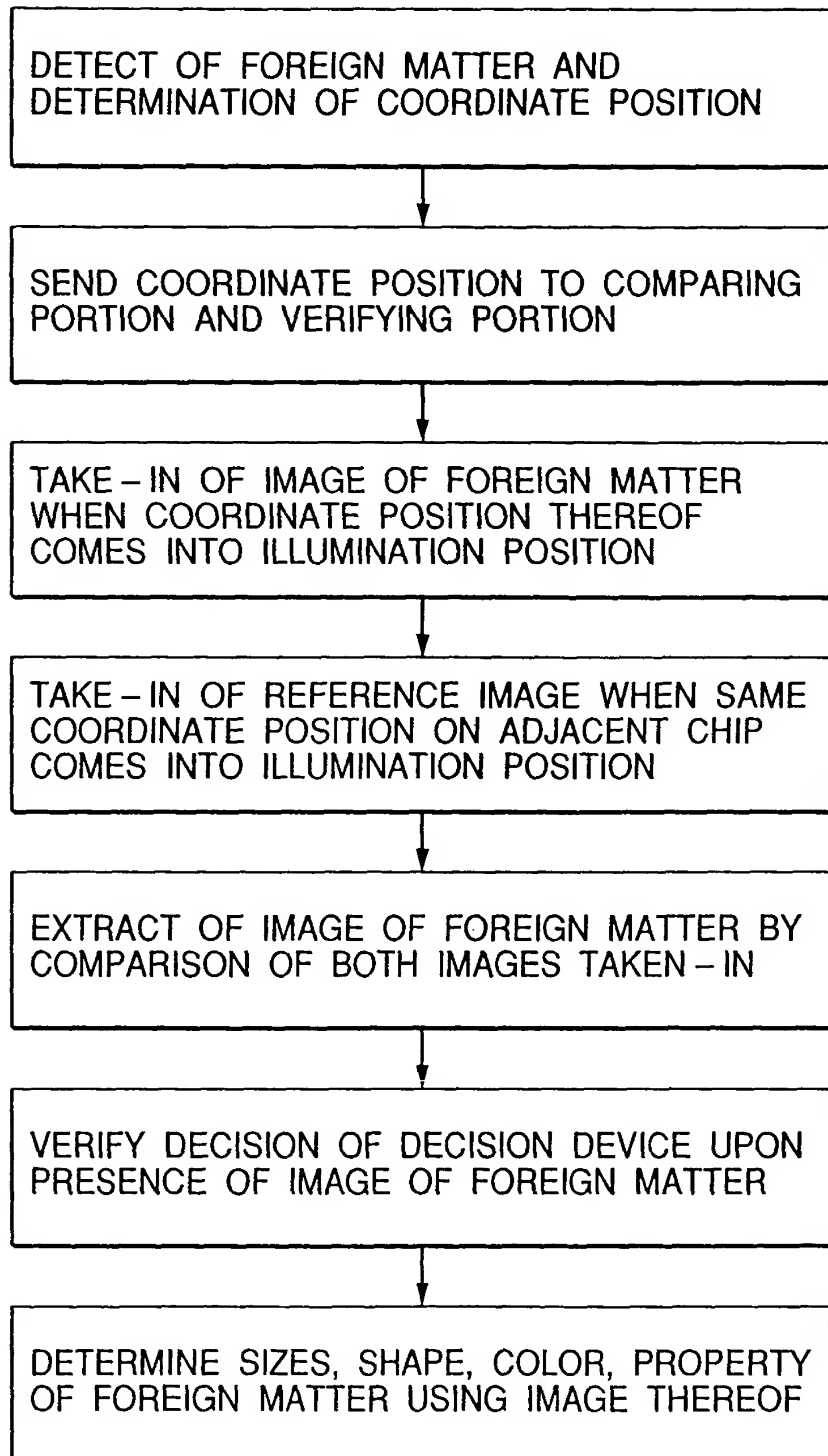
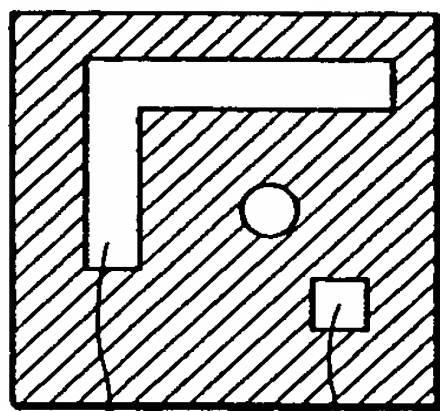
FIG. 2

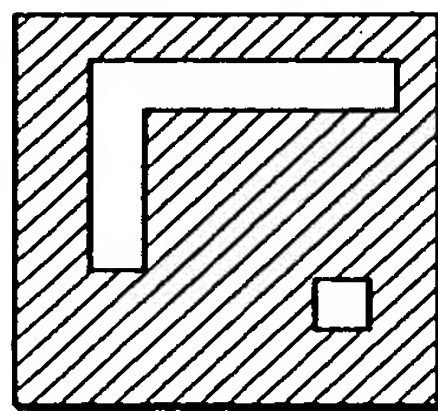
FIG. 3(a)



4a

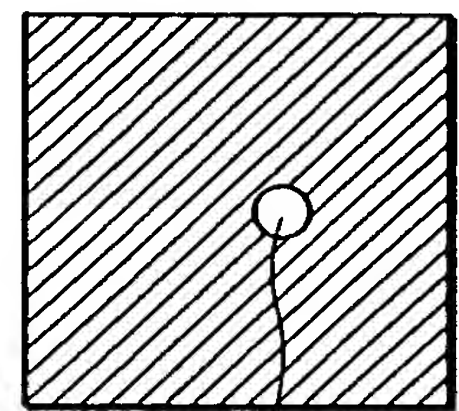
4b

FIG. 3(b)



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FIG. 3(c)



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FIG. 3(d)

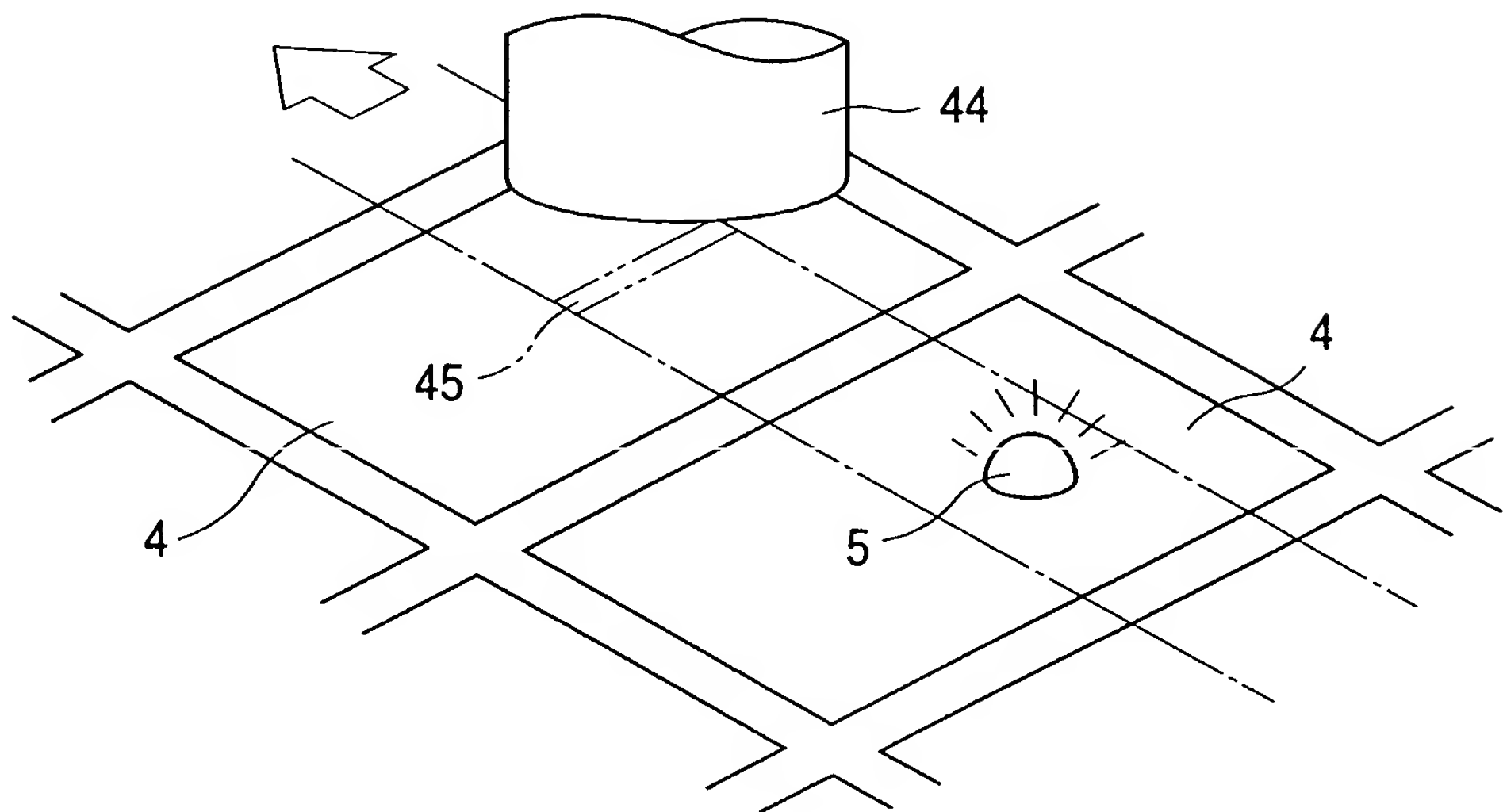


FIG. 4(a)

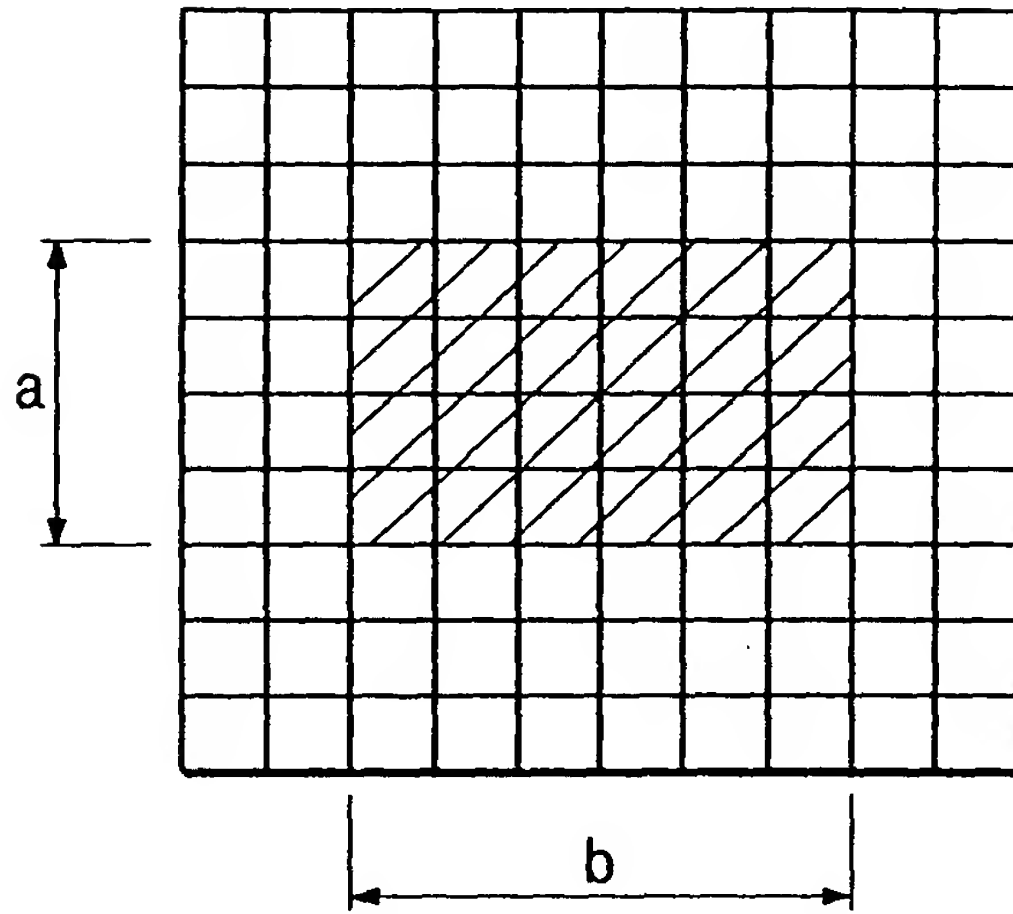


FIG. 4(b)

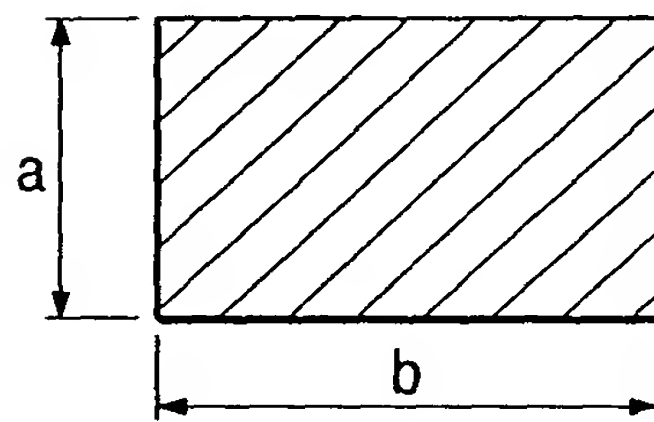


FIG. 4(c)

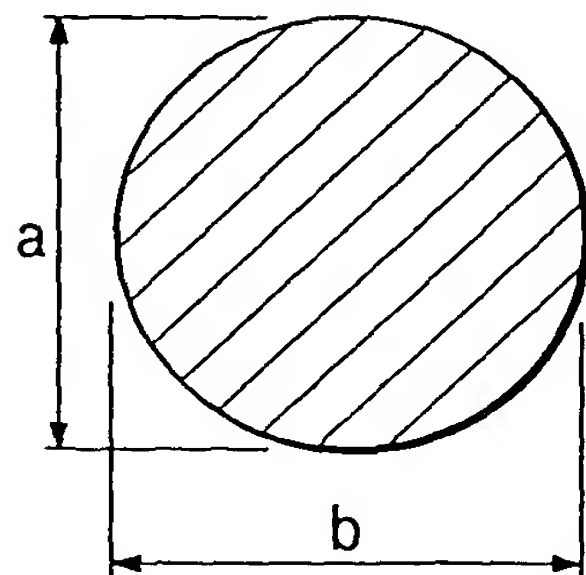


FIG. 4(d)

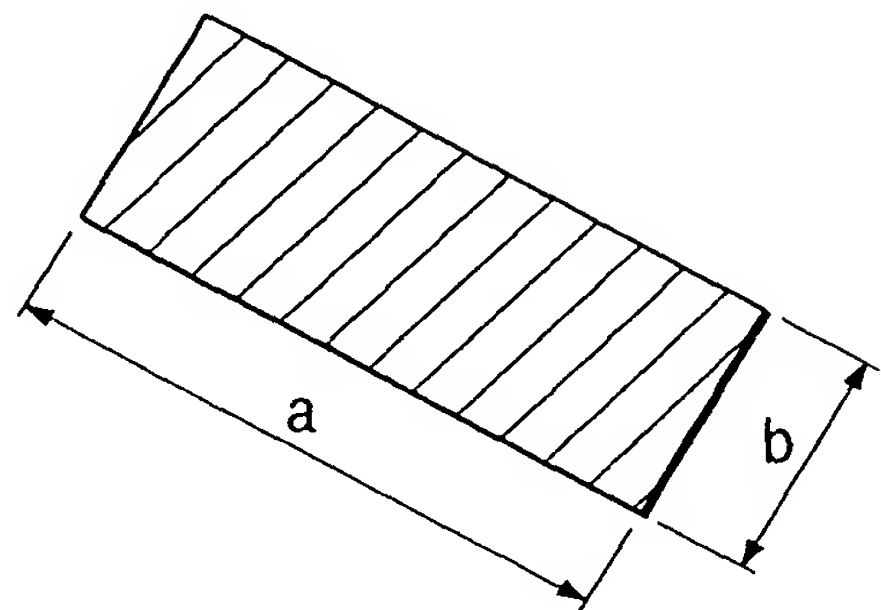
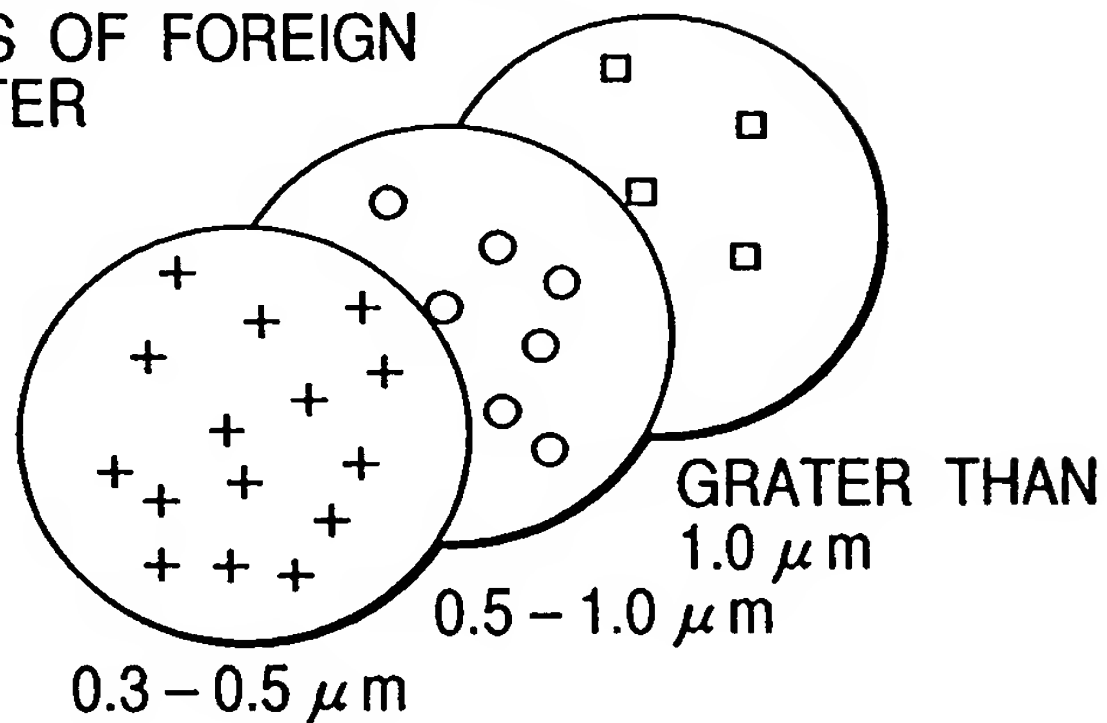
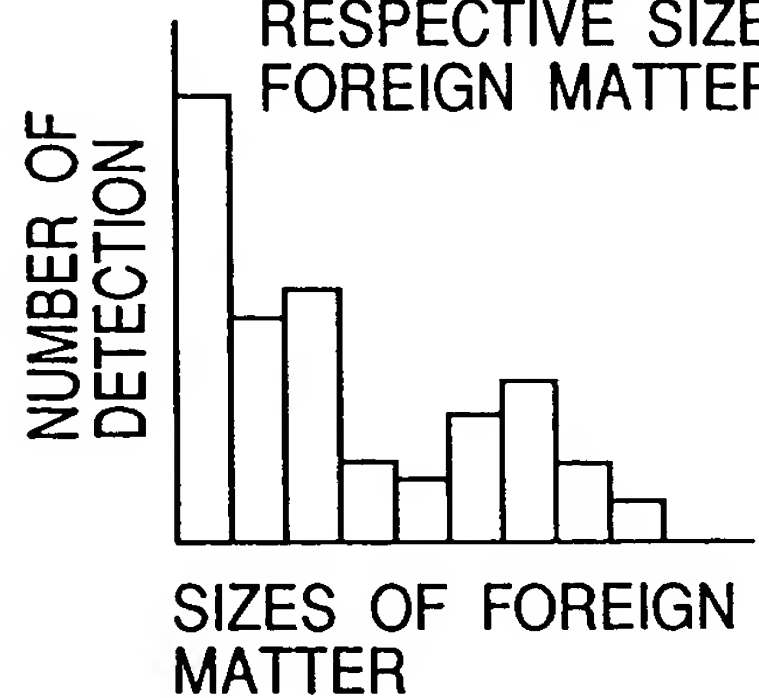


FIG. 5(a)

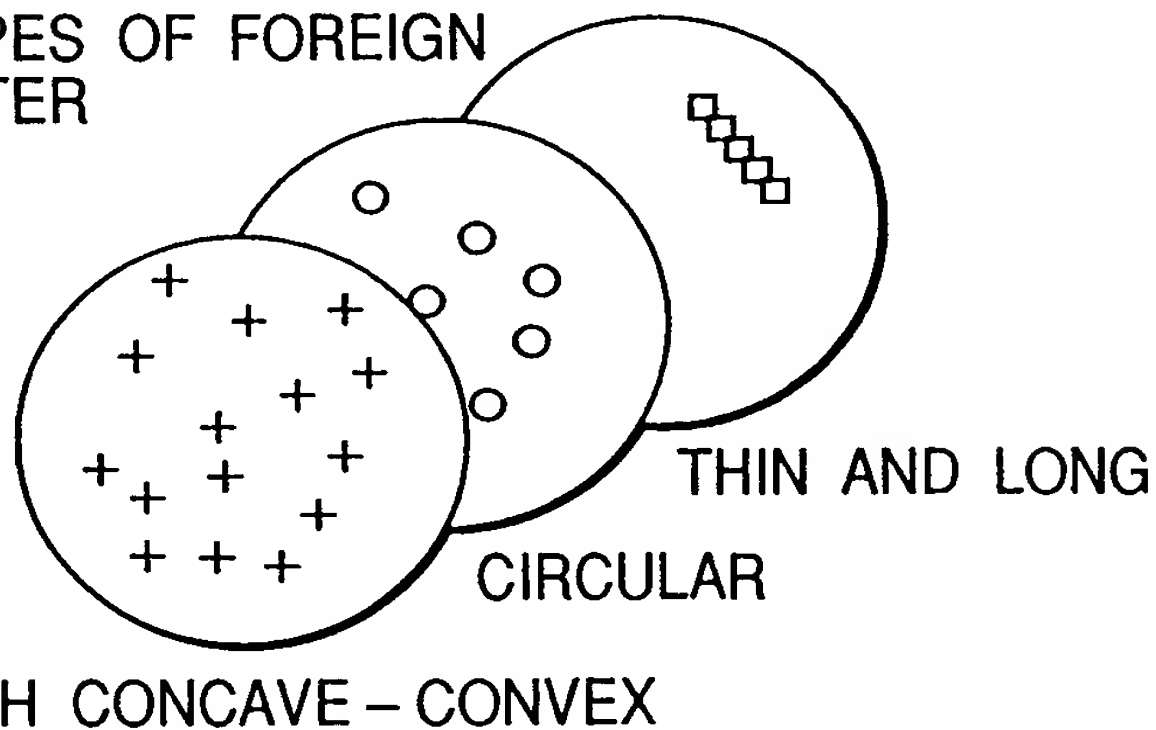
MAPS FOR RESPECTIVE
SIZES OF FOREIGN
MATTER

**FIG. 5(b)**

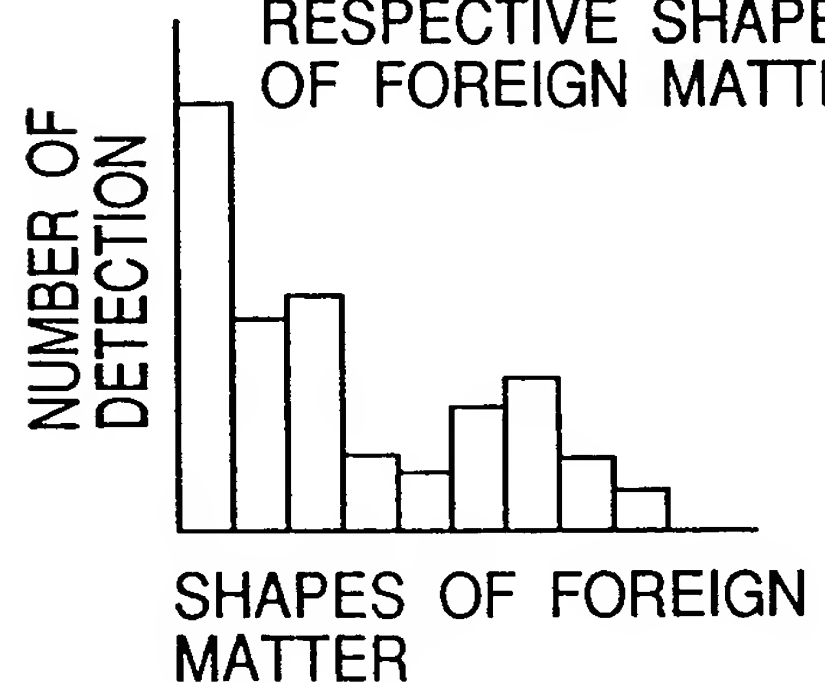
HISTOGRAM FOR
RESPECTIVE SIZES OF
FOREIGN MATTER

**FIG. 5(c)**

MAPS FOR RESPECTIVE
SHAPES OF FOREIGN
MATTER

**FIG. 5(d)**

HISTOGRAM FOR
RESPECTIVE SHAPES
OF FOREIGN MATTER

**FIG. 5(e)**

GRAPH OF RESULT OF INSPECTION IN TIME SEQUENCE

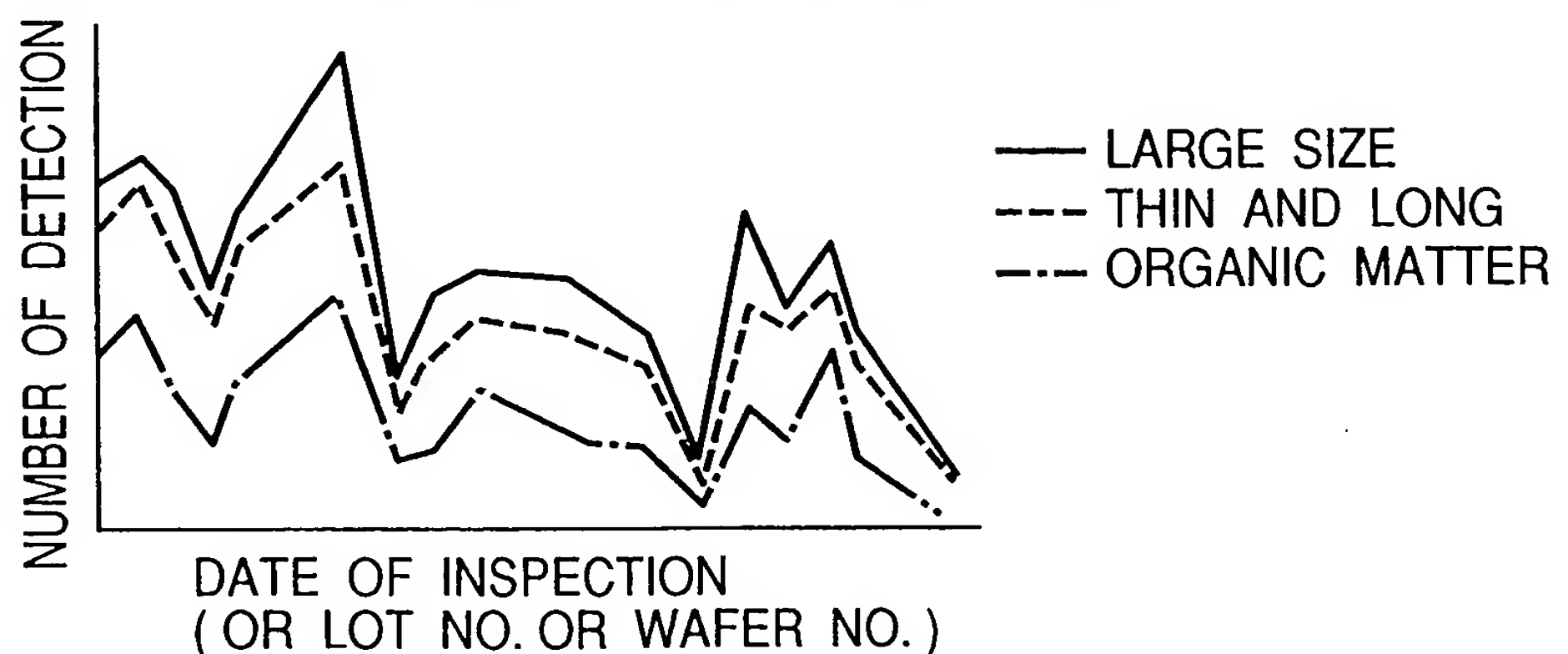


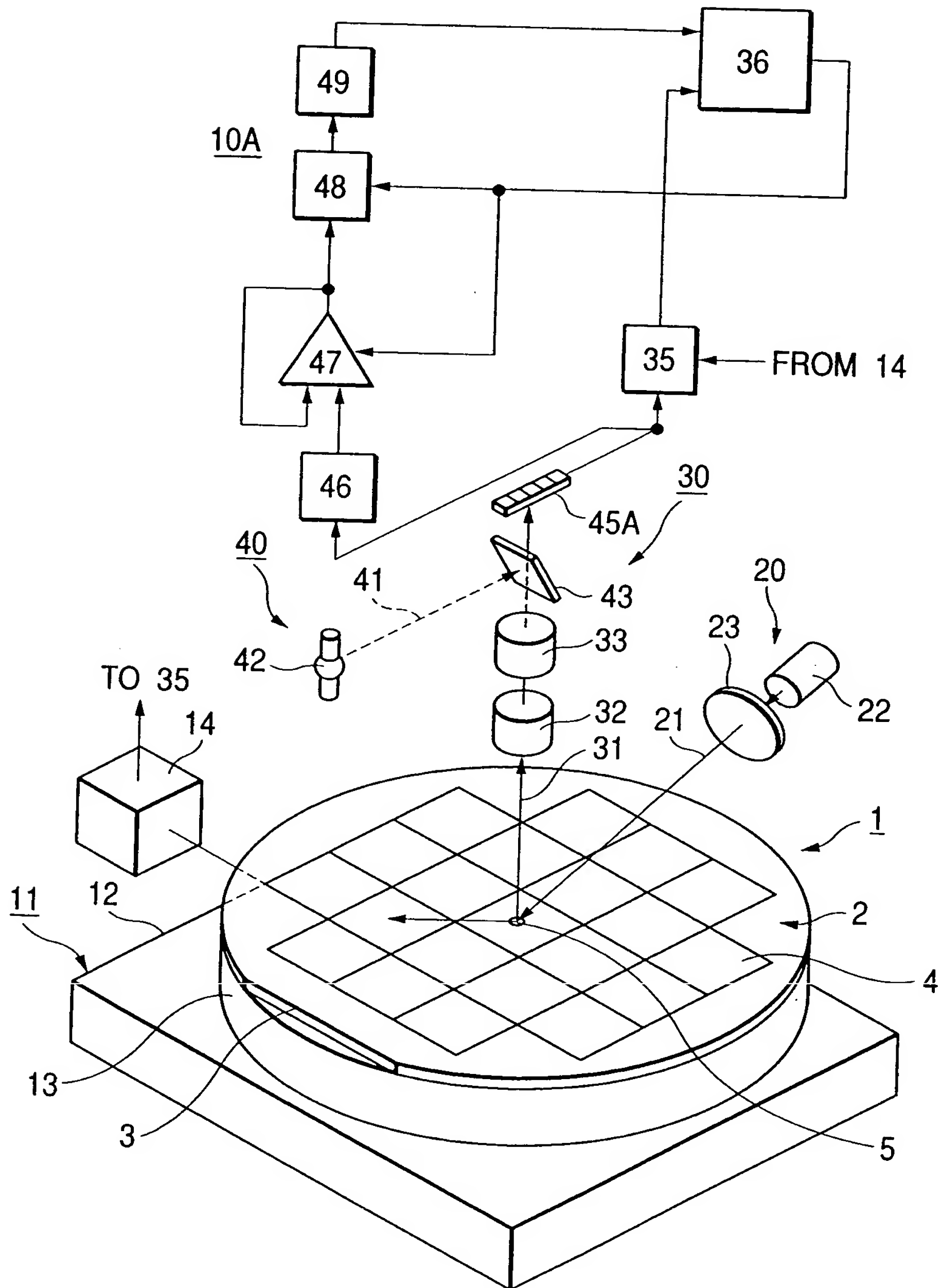
FIG. 6

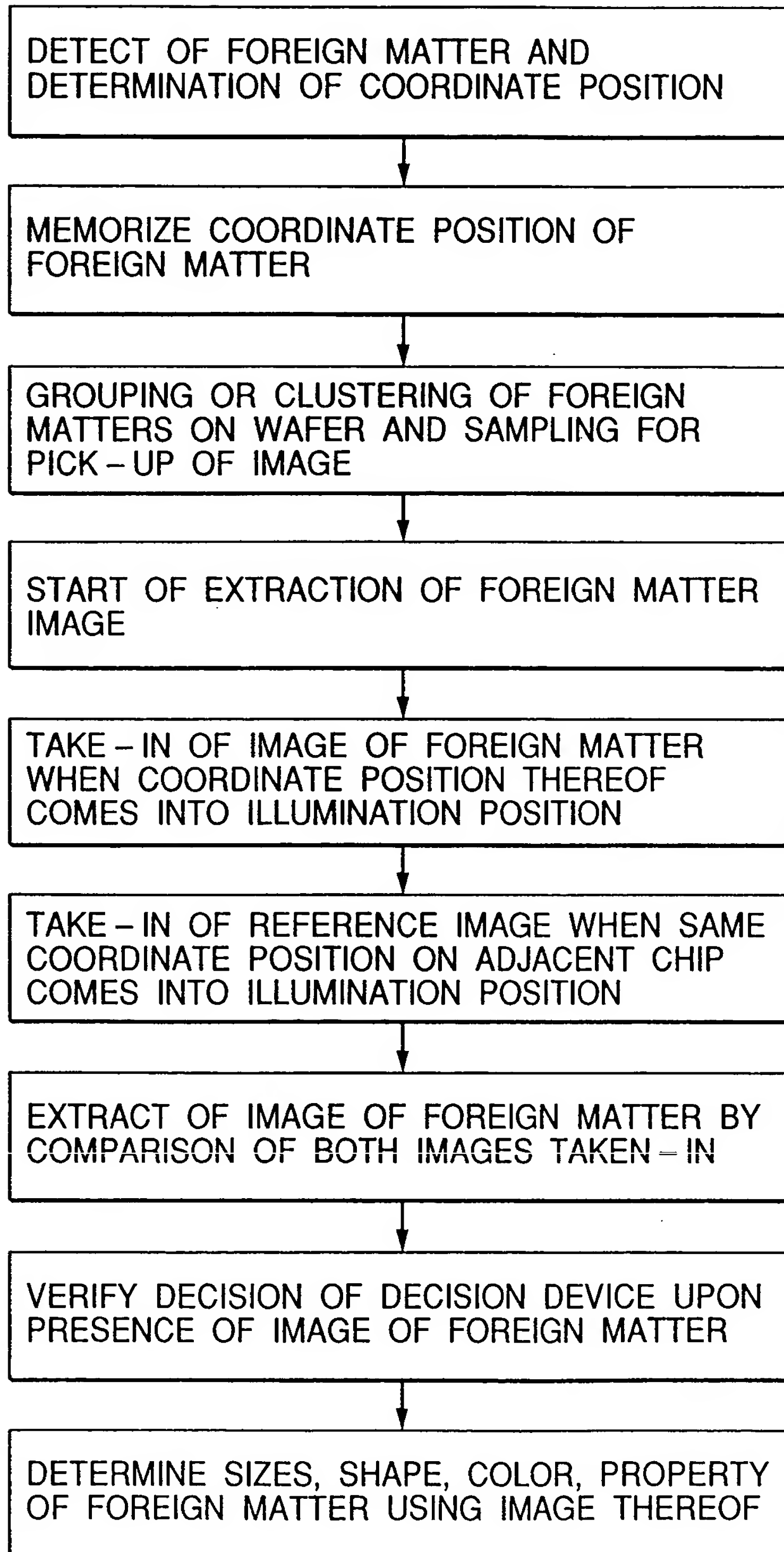
FIG. 7

FIG. 8(a)

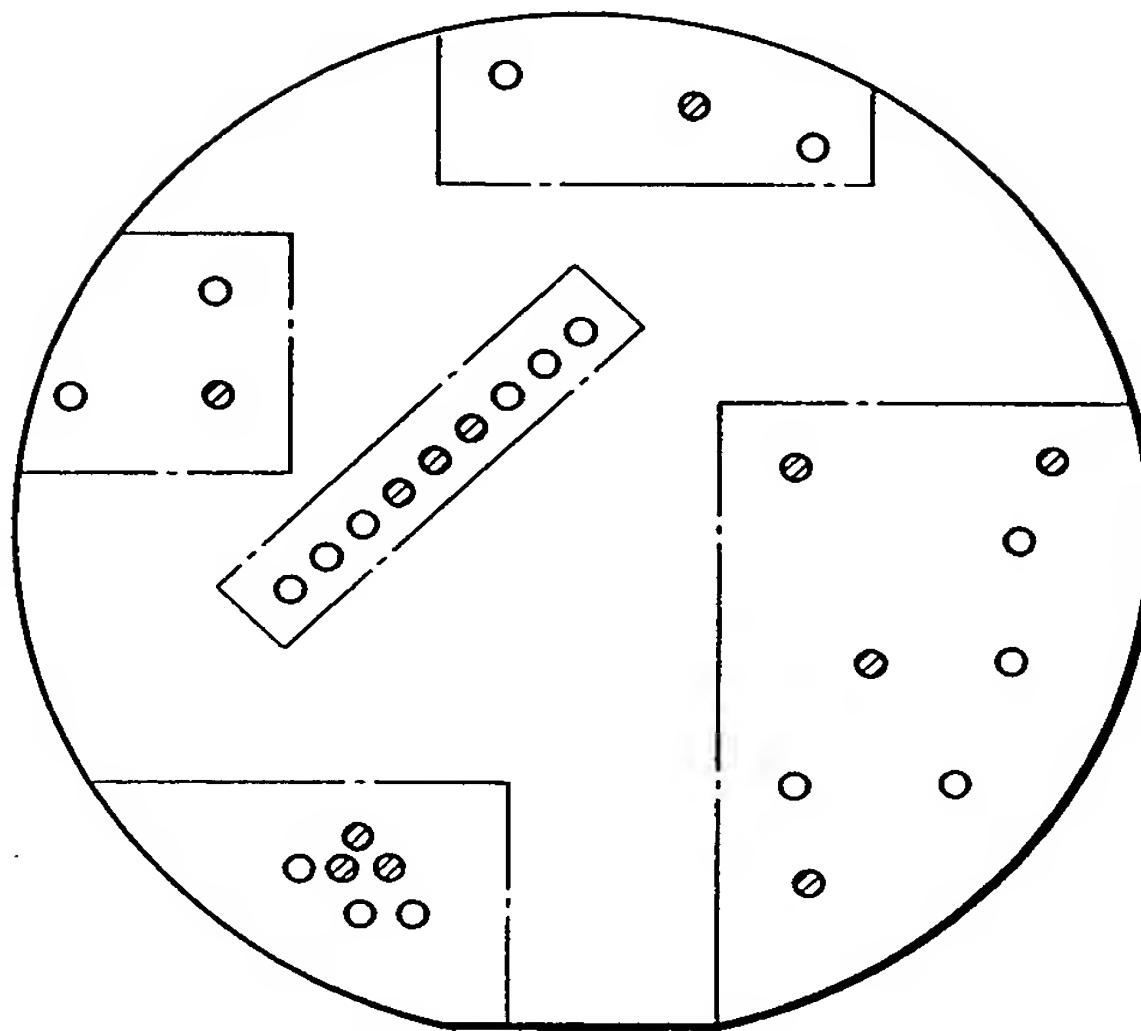


FIG. 8(b)

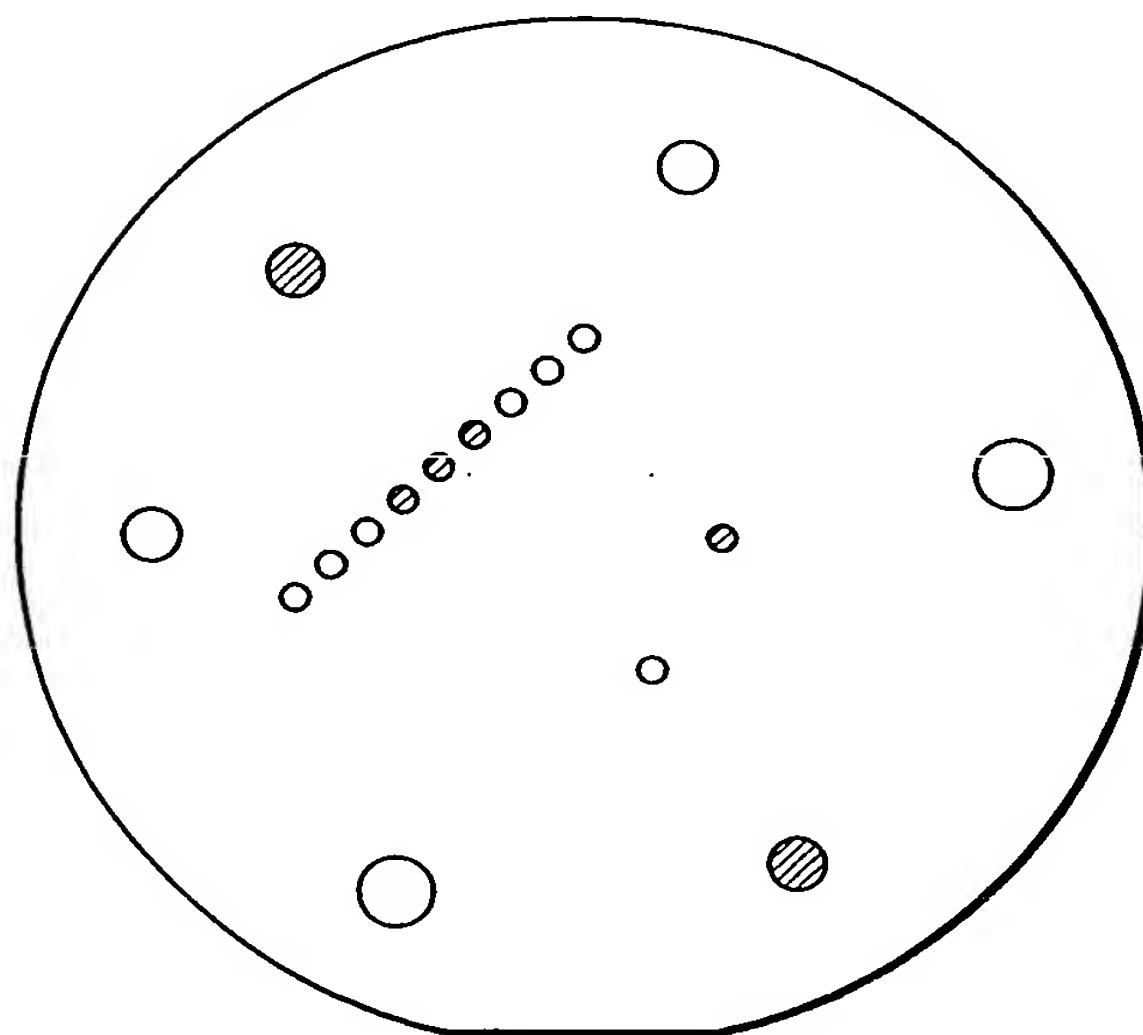


FIG. 10

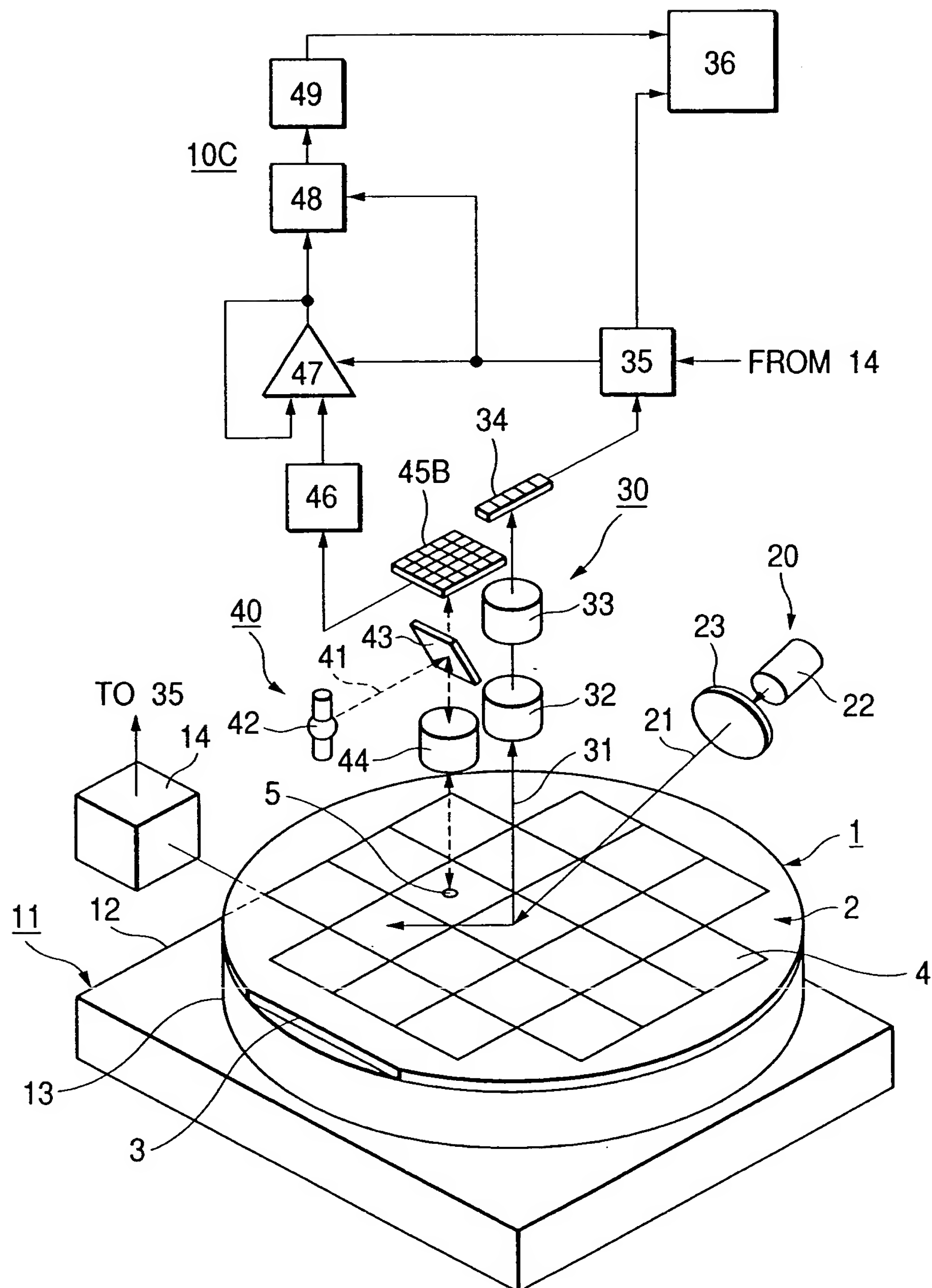


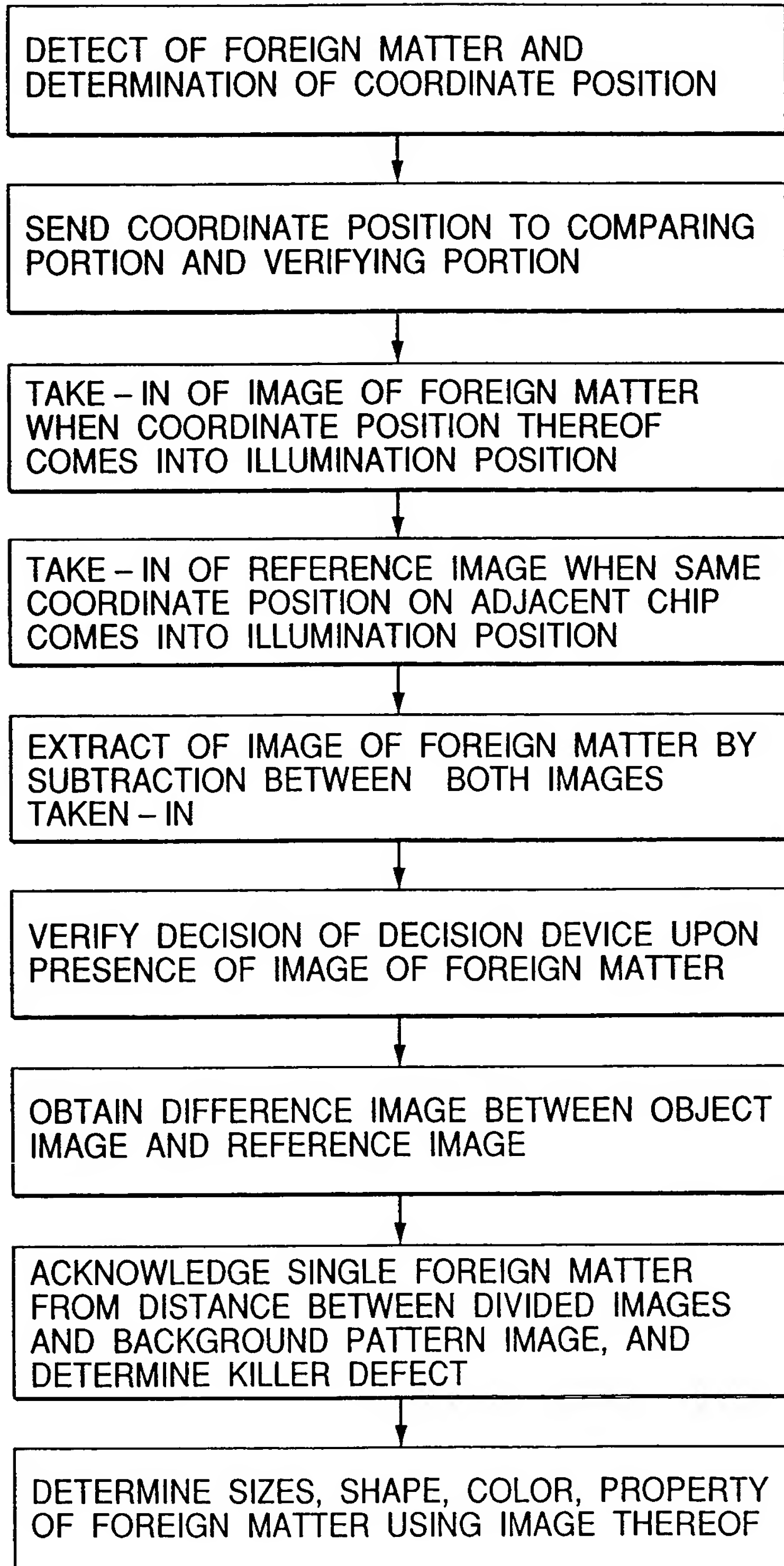
FIG. 11

FIG. 12(a) FIG. 12(b) FIG. 12(c) FIG. 12(d)

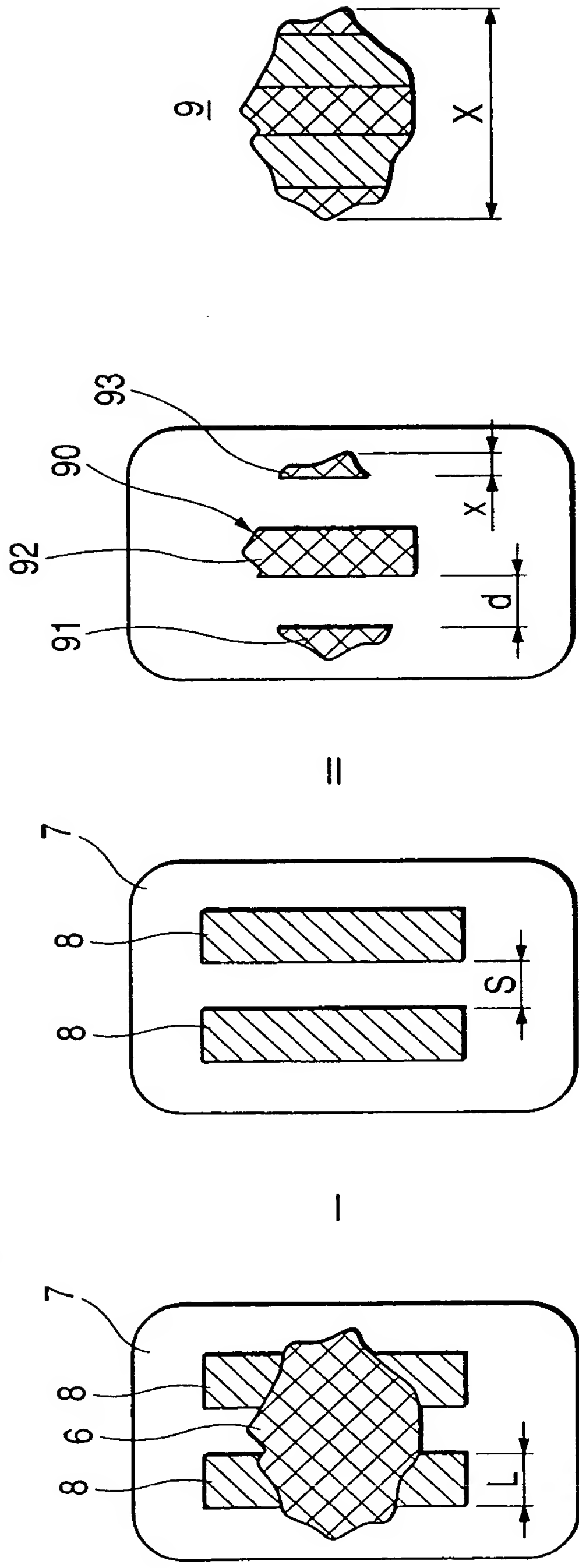


FIG. 13(a) FIG. 13(b) FIG. 13(c) FIG. 13(d)

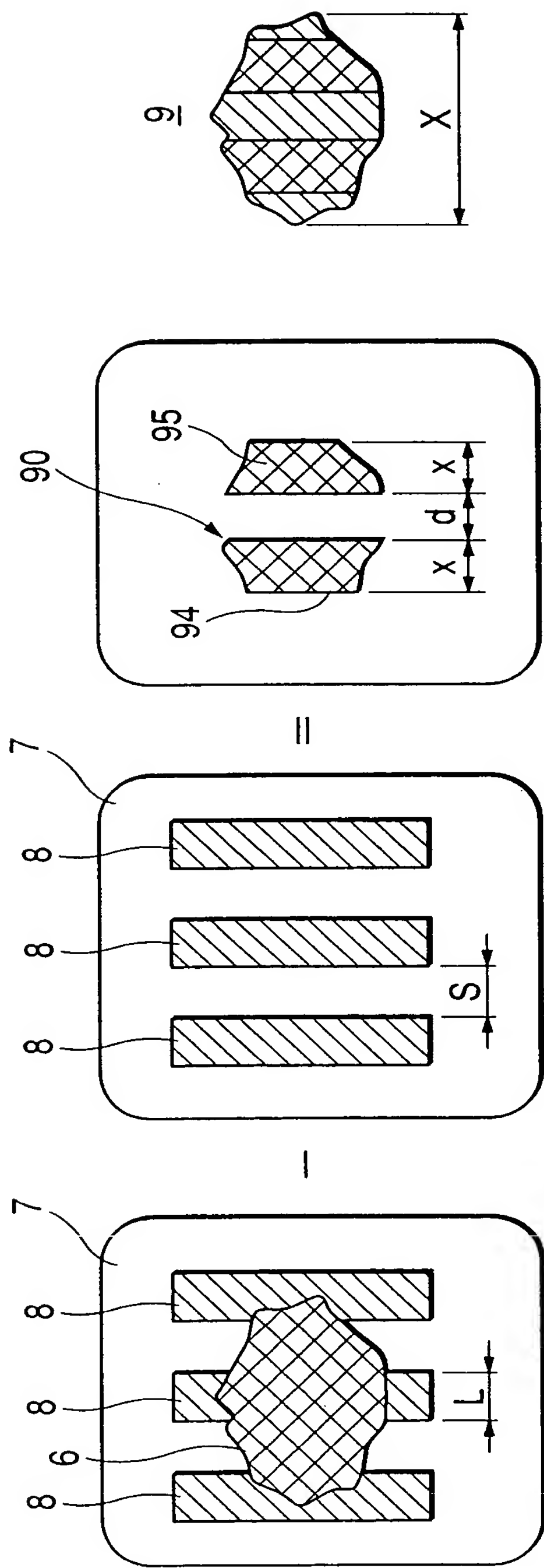
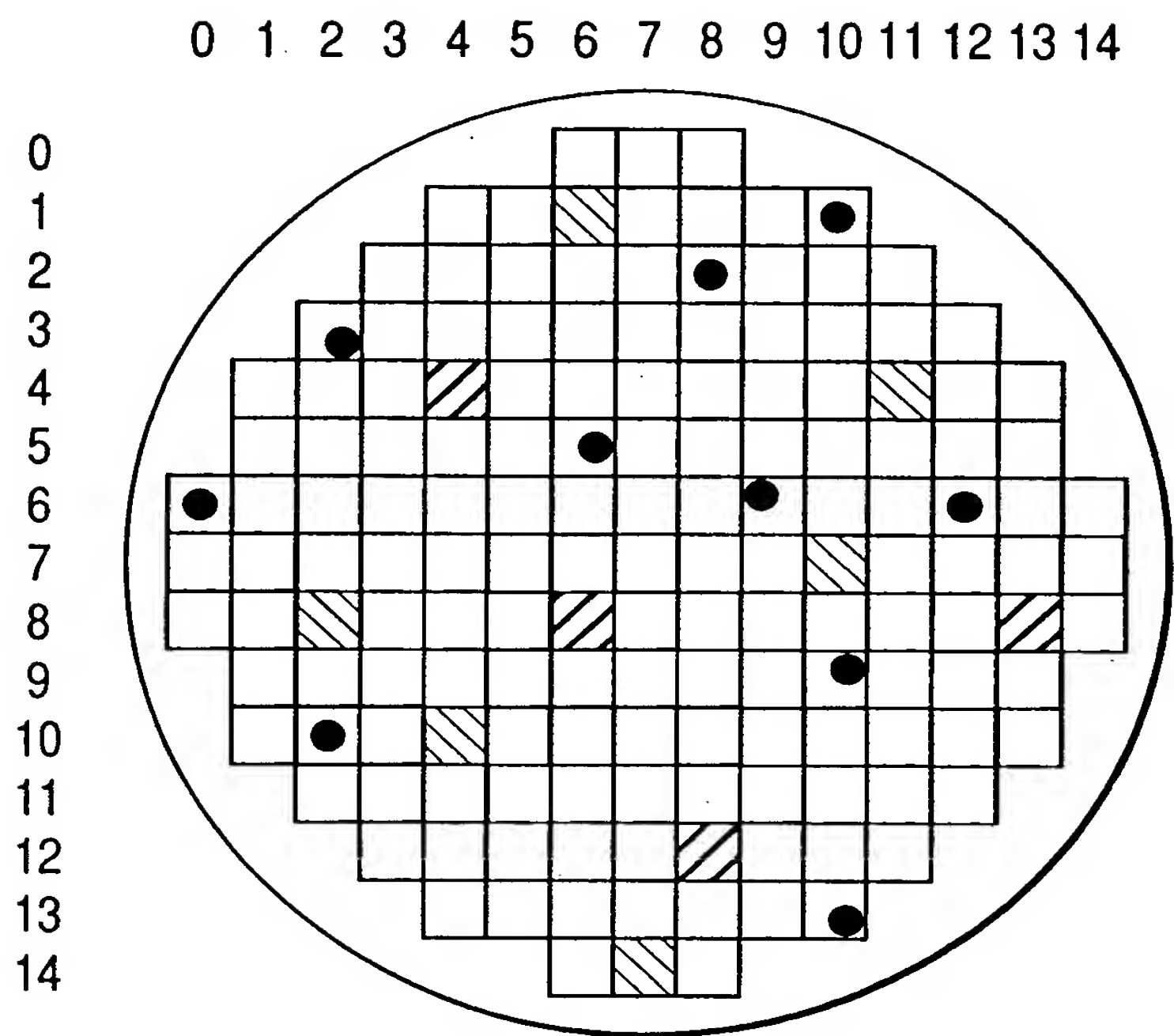




FIG. 14



 KILLER DEFECT CHIP
(OMITTED ILLUSTRATION OF DETECTED FOREIGN MATTER)

 POSSIBLE DEFECT CHIP
(OMITTED ILLUSTRATION OF DETECTED FOREIGN MATTER)

 GOOD CHIP

DETECTED FOREIGN MATTER

FIG. 15(a) FIG. 15(b) FIG. 15(c)

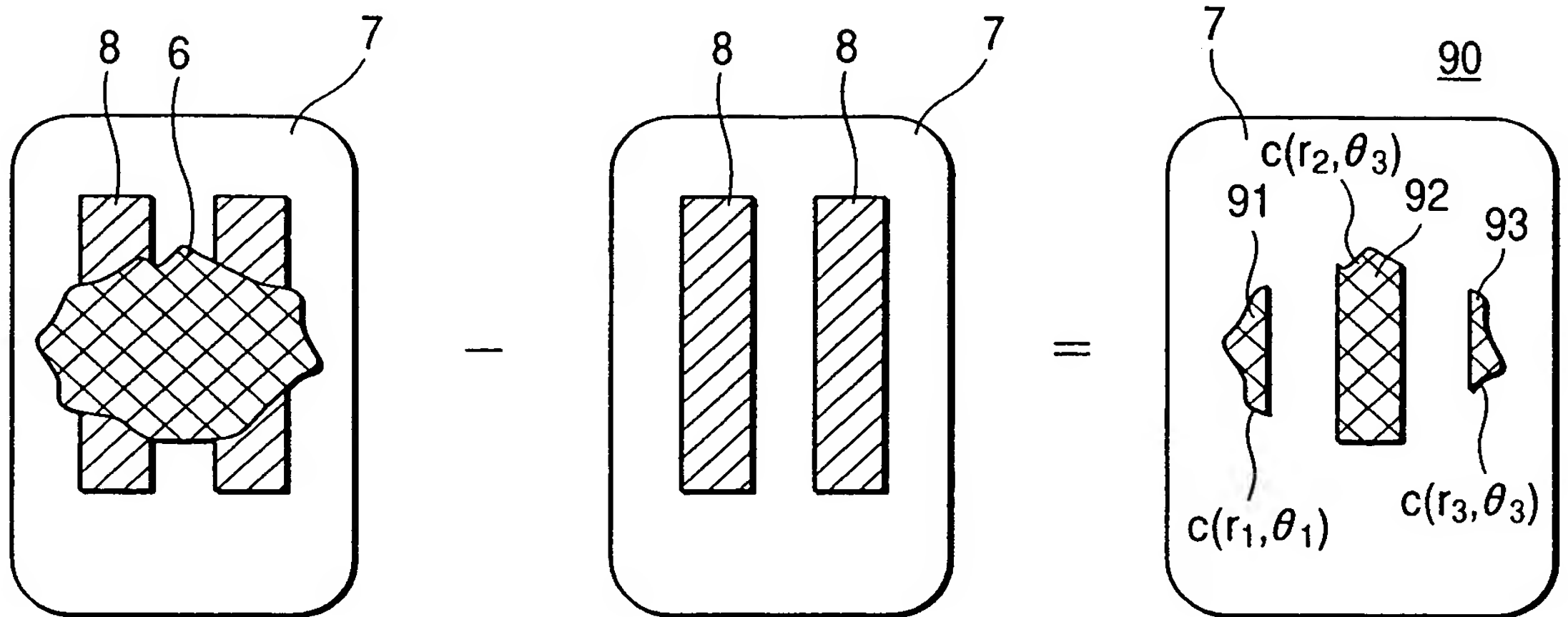


FIG. 15(d)

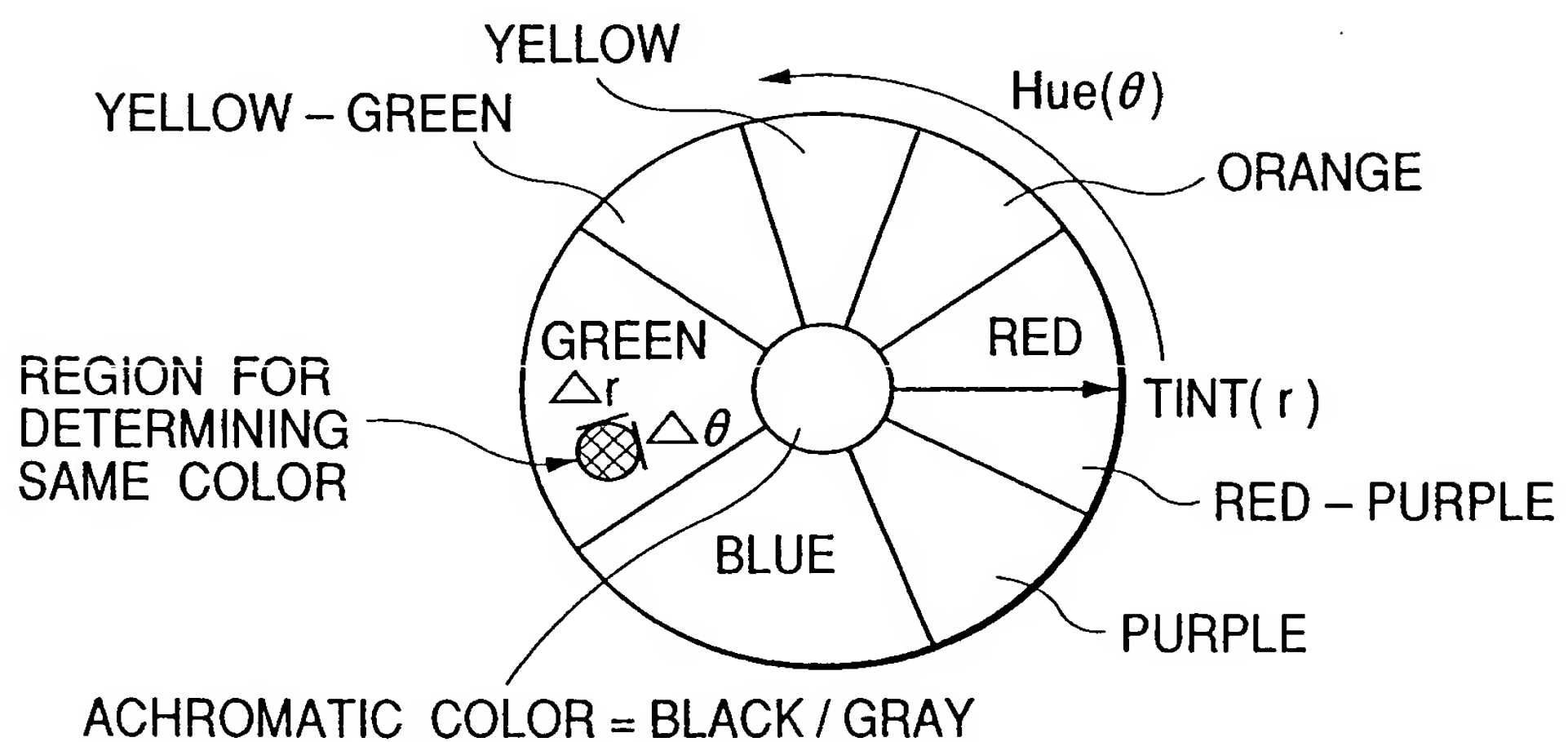


FIG. 16(a) FIG. 16(b) FIG. 16(c) FIG. 16(d)

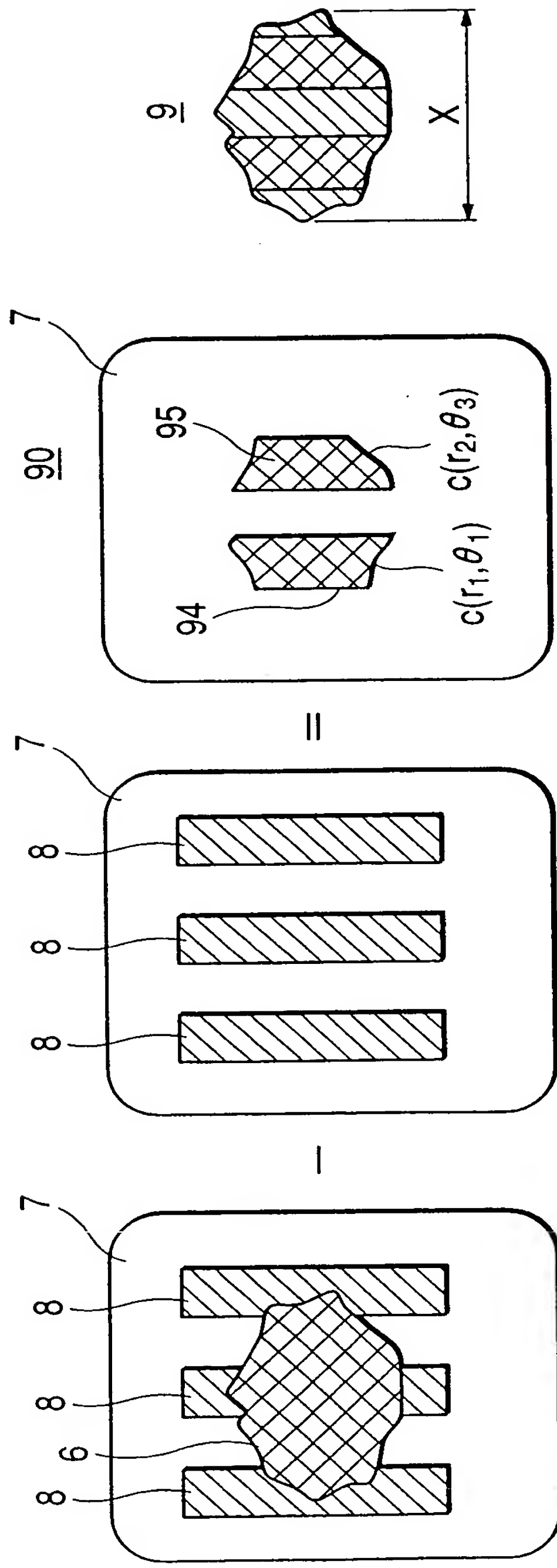


FIG. 17(a) FIG. 17(b) FIG. 17(c) FIG. 17(d)

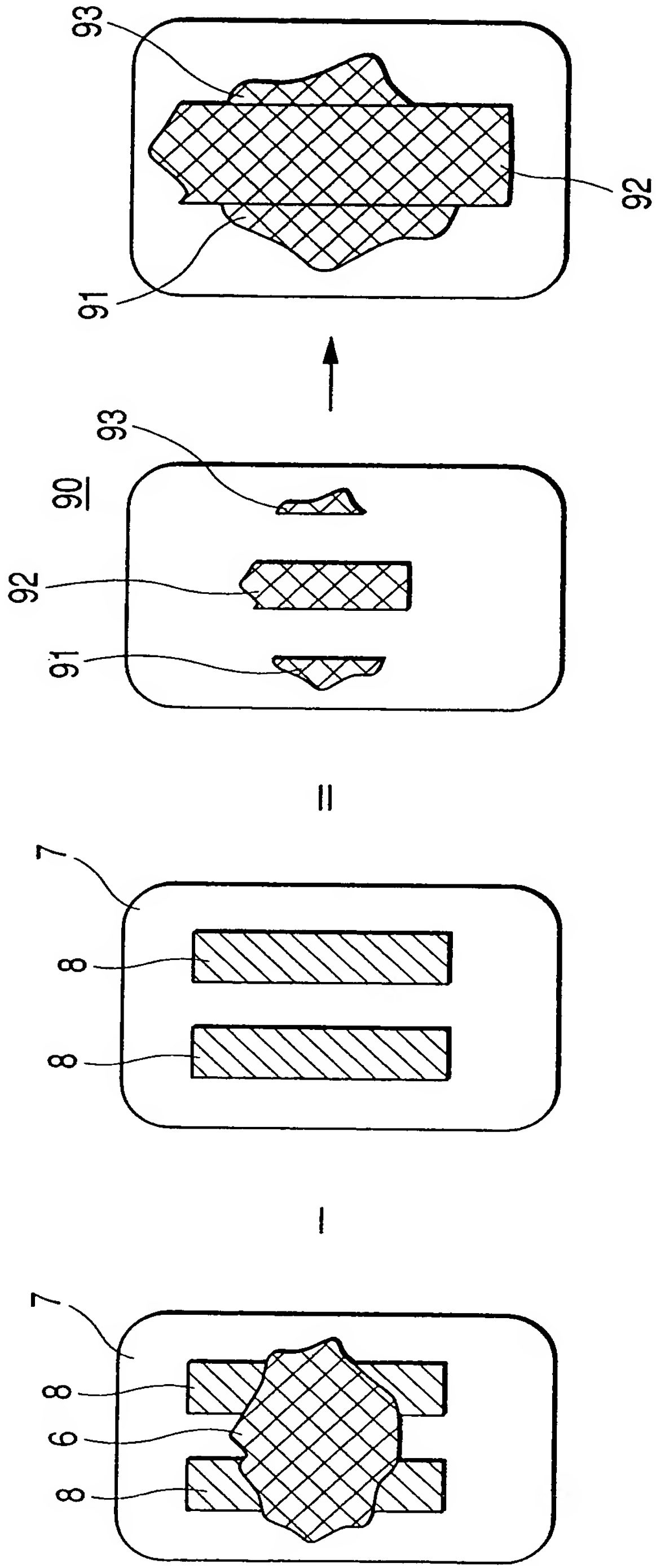
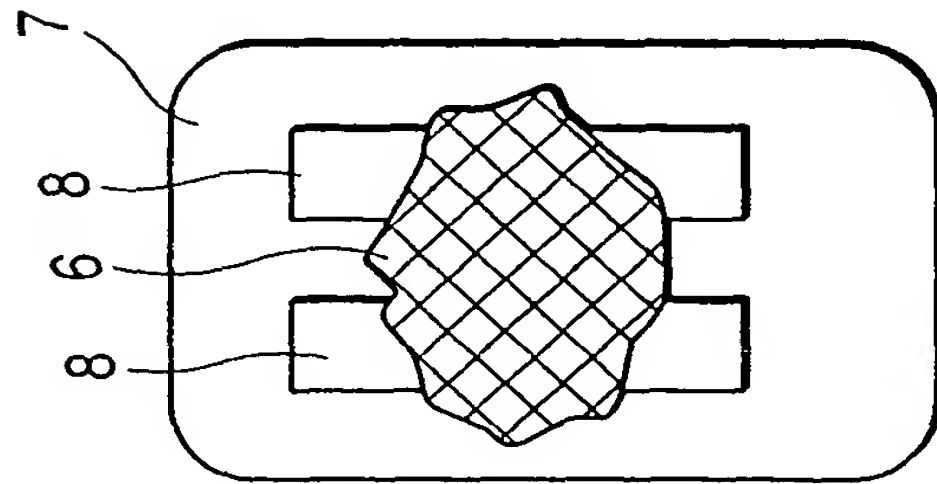
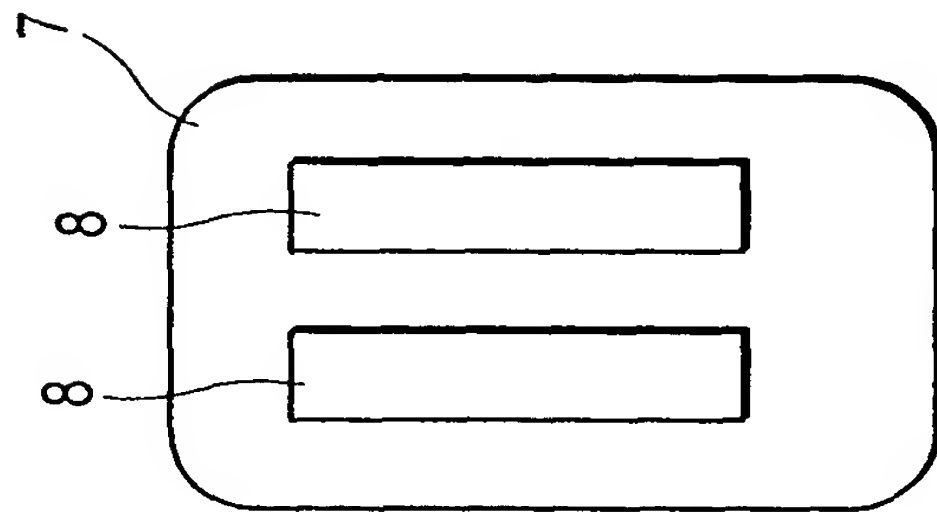


FIG. 18(a) FIG. 18(b) FIG. 18(c) FIG. 18(d)



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